

FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

Sheet 1 of 1

APPLICATION NO.

1514.1030

FIRST NAMED INVENTOR

Ji Yong PARK et al.

FILING DATE

December 15, 2003

2815

			U.S. PA	TENT DOCUM	ENTS			
*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAI	ME	CLASS	SUB- CLASS	FILING DATE
	AA							
	AB							
	AC							
	AD							
	AE							
	AF							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)			TRANSL YES	ATION NO
	AJ	Wang, Mingxiang and Man Wong. "Characterization of an Individual Grain Boundary in Metal-Induced Laterally Crystallized Polycrystalline Silicon Thin-Film Devices." IEEE Transactions on Electron Devices. Vol. 48, No. 8, August 2001, pages 1655-1660.		
	AK	Cho, Hans S. et al. "Sequential Lateral Solidification of Ultra-Thin a-Si Films." Mat. Res. Soc. Symp. Proc. Vol. 621, 2001, pages 1-6.		

EXAMINER	DATE CONSIDERED		
much Chle	8/5/06		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

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Sheet 1 of 1 application no.

1514.1030 10/734,162

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U.S. PATENT DOCUMENTS

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	AA						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	TRANSLATION YES NO	ABSTRACT
me	AG	JP 11-354800	12/1999	JAPAN		Х
	АН					
	Al					
	AJ					
·	AK					
	AL					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)				TRANSLATION YES NO	
m	AM	Office Action issued in Chinese Patent Application No. 200310109779.2 on September 2, 2005.	x		

EXAMINER	DATE CONSIDERED			
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